

CSD19538Q2 100V N-Channel NexFET™ Power MOSFET

1 Features

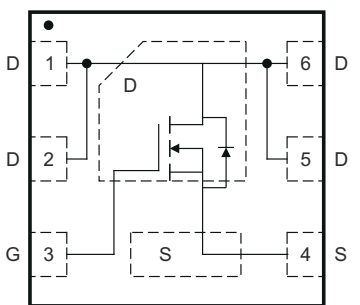
- Ultra-low Q_g and Q_{gd}
- Low-thermal resistance
- Avalanche rated
- Lead free
- RoHS compliant
- Halogen free
- SON 2mm × 2mm plastic package

2 Applications

- Power over ethernet (PoE)
- Power sourcing equipment (PSE)
- Motor control

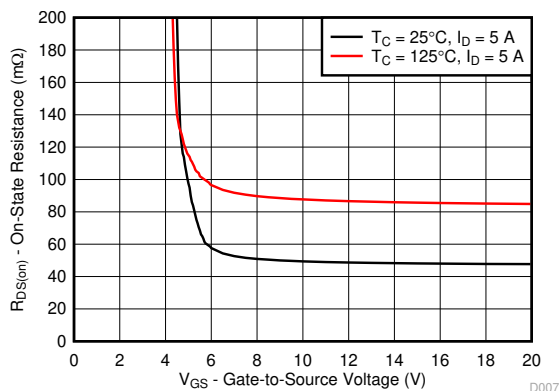
Description

This 100V, 49mΩ, SON 2mm × 2mm NexFET™ power MOSFET is designed to minimize losses in power conversion applications.



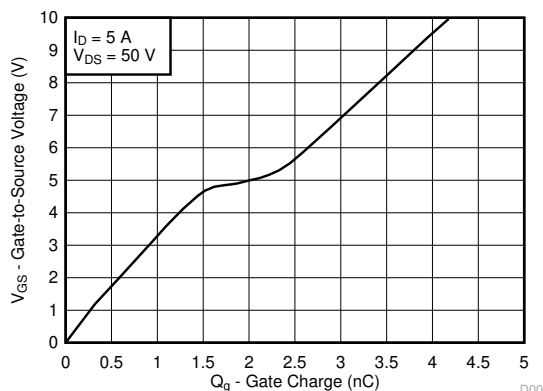
P0108-01

Figure 3-1. Top View



D007

$R_{DS(on)}$ vs V_{GS}



D004

Gate Charge

Product Summary

| $T_A = 25^\circ\text{C}$ | | TYPICAL VALUE | | UNIT |
|--------------------------|-------------------------------|-----------------------|----|------|
| V_{DS} | Drain-to-Source Voltage | 100 | | V |
| Q_g | Gate Charge Total (10V) | 4.3 | | nC |
| Q_{gd} | Gate Charge Gate-to-Drain | 0.8 | | nC |
| $R_{DS(on)}$ | Drain-to-Source On Resistance | $V_{GS} = 6\text{V}$ | 58 | mΩ |
| | | $V_{GS} = 10\text{V}$ | 49 | |
| $V_{GS(th)}$ | Threshold Voltage | 3.2 | | V |

Device Information⁽¹⁾

| DEVICE | QTY | MEDIA | PACKAGE | SHIP |
|-------------|--------|--------------|---|---------------------|
| CSD19538Q2 | 3000 | 7 Inch Reel | SON 2.00mm x 2.00mm Plastic Package | Tape and Reel |
| CSD19538Q2T | 250 | | | |
| CSD19538Q2R | 10,000 | 13 Inch Reel | | |

- (1) For all available packages, see the orderable addendum at the end of the data sheet.

Absolute Maximum Ratings

| $T_A = 25^\circ\text{C}$ | | VALUE | UNIT |
|--------------------------|--|------------|------|
| V_{DS} | Drain-to-Source Voltage | 100 | V |
| V_{GS} | Gate-to-Source Voltage | ±20 | V |
| I_D | Continuous Drain Current (Package Limited) | 14.4 | A |
| | Continuous Drain Current (Silicon Limited), $T_C = 25^\circ\text{C}$ | 13.1 | |
| | Continuous Drain Current ⁽¹⁾ | 4.6 | |
| I_{DM} | Pulsed Drain Current ⁽²⁾ | 34.4 | A |
| P_D | Power Dissipation ⁽¹⁾ | 2.5 | W |
| | Power Dissipation, $T_C = 25^\circ\text{C}$ | 20.2 | |
| T_J, T_{stg} | Operating Junction Temperature, Storage Temperature | -55 to 150 | °C |
| E_{AS} | Avalanche Energy, Single Pulse $I_D = 12.6\text{A}, L = 0.1\text{mH}, R_G = 25\Omega$ | 8 | mJ |

- (1) Typical $R_{\theta JA} = 50^\circ\text{C/W}$ on a 1 inch², 2oz Cu pad on a 0.06 inch thick FR4 PCB.
 (2) Max $R_{\theta JC} = 6.2^\circ\text{C/W}$, pulse duration $\leq 100\mu\text{s}$, duty cycle $\leq 1\%$.



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3 Specifications

3.1 Electrical Characteristics

$T_A = 25^\circ\text{C}$ (unless otherwise stated)

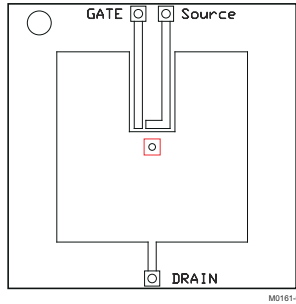
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------------------|----------------------------------|---|-----|------|------|------------|
| STATIC CHARACTERISTICS | | | | | | |
| BV_{DSS} | Drain-to-source voltage | $V_{GS} = 0V, I_D = 250\mu A$ | 100 | | | V |
| I_{DSS} | Drain-to-source leakage current | $V_{GS} = 0V, V_{DS} = 80V$ | | | 1 | μA |
| I_{GSS} | Gate-to-source leakage current | $V_{DS} = 0V, V_{GS} = 20V$ | | | 100 | nA |
| $V_{GS(th)}$ | Gate-to-source threshold voltage | $V_{DS} = V_{GS}, I_D = 250\mu A$ | 2.8 | 3.2 | 3.8 | V |
| $R_{DS(on)}$ | Drain-to-source on resistance | $V_{GS} = 6V, I_D = 5A$ | | 58 | 72 | m Ω |
| | | $V_{GS} = 10V, I_D = 5A$ | | 49 | 59 | |
| g_{fs} | Transconductance | $V_{DS} = 10V, I_D = 5A$ | | 19 | | S |
| DYNAMIC CHARACTERISTICS | | | | | | |
| C_{iss} | Input capacitance | $V_{GS} = 0V, V_{DS} = 50V, f = 1MHz$ | | 349 | 454 | pF |
| C_{oss} | Output capacitance | | | 69 | 90 | pF |
| C_{rss} | Reverse transfer capacitance | | | 12.6 | 16.4 | pF |
| R_G | Series gate resistance | | | 4.6 | 9.2 | Ω |
| Q_g | Gate charge total (10V) | $V_{DS} = 50V, I_D = 5A$ | | 4.3 | 5.6 | nC |
| Q_{gd} | Gate charge gate-to-drain | | | 0.8 | | nC |
| Q_{gs} | Gate charge gate-to-source | | | 1.6 | | nC |
| $Q_{g(th)}$ | Gate charge at V_{th} | | | 1.0 | | nC |
| Q_{oss} | Output charge | $V_{DS} = 50V, V_{GS} = 0V$ | | 12.3 | | nC |
| $t_{d(on)}$ | Turnon delay time | $V_{DS} = 50V, V_{GS} = 10V,$ $I_{DS} = 5A, R_G = 0\Omega$ | | 5 | | ns |
| t_r | Rise time | | | 3 | | ns |
| $t_{d(off)}$ | Turnoff delay time | | | 7 | | ns |
| t_f | Fall time | | | 2 | | ns |
| DIODE CHARACTERISTICS | | | | | | |
| V_{SD} | Diode forward voltage | $I_{SD} = 5A, V_{GS} = 0V$ | | 0.85 | 1.0 | V |
| Q_{rr} | Reverse recovery charge | $V_{DS} = 50V, I_F = 5A,$ $di/dt = 300A/\mu s$ | | 94 | | nC |
| t_{rr} | Reverse recovery time | | | 32 | | ns |

3.2 Thermal Information

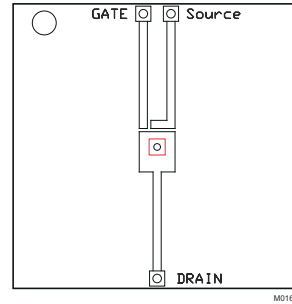
$T_A = 25^\circ\text{C}$ (unless otherwise stated)

| THERMAL METRIC | | MIN | TYP | MAX | UNIT |
|-----------------|---|-----|-----|-----|--------------------|
| $R_{\theta JC}$ | Junction-to-case thermal resistance ⁽¹⁾ | | | 6.2 | $^\circ\text{C/W}$ |
| $R_{\theta JA}$ | Junction-to-ambient thermal resistance ^{(1) (2)} | | | 65 | $^\circ\text{C/W}$ |

- (1) $R_{\theta JC}$ is determined with the device mounted on a 1in^2 (6.45cm^2), 2oz (0.071mm) thick Cu pad on a $1.5\text{in} \times 1.5\text{in}$ ($3.81\text{cm} \times 3.81\text{cm}$), 0.06in (1.52mm) thick FR4 PCB. $R_{\theta JC}$ is specified by design, whereas $R_{\theta JA}$ is determined by the user's board design.
- (2) Device mounted on FR4 material with 1in^2 (6.45cm^2), 2oz (0.071mm) thick Cu.



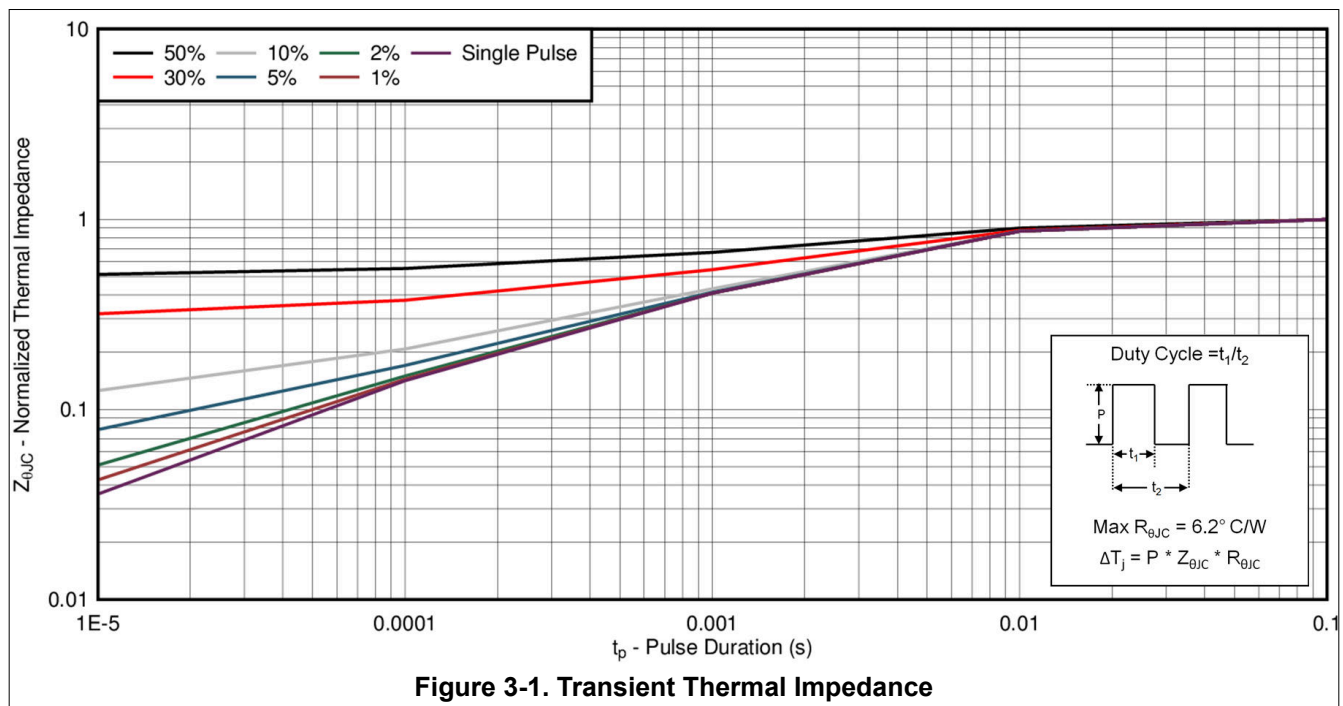
Max $R_{\theta JA} = 65^{\circ}\text{C/W}$ when mounted on 1in^2 (6.45cm^2) of 2oz (0.071mm) thick Cu.



Max $R_{\theta JA} = 250^{\circ}\text{C/W}$ when mounted on a minimum pad area of 2oz (0.071mm) thick Cu.

3.3 Typical MOSFET Characteristics

$T_A = 25^{\circ}\text{C}$ (unless otherwise stated)



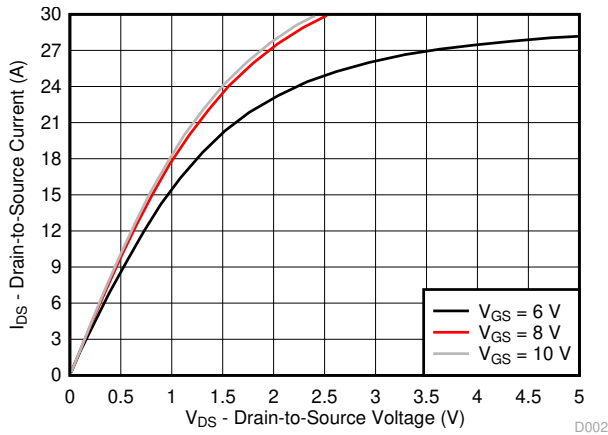


Figure 3-2. Saturation Characteristics

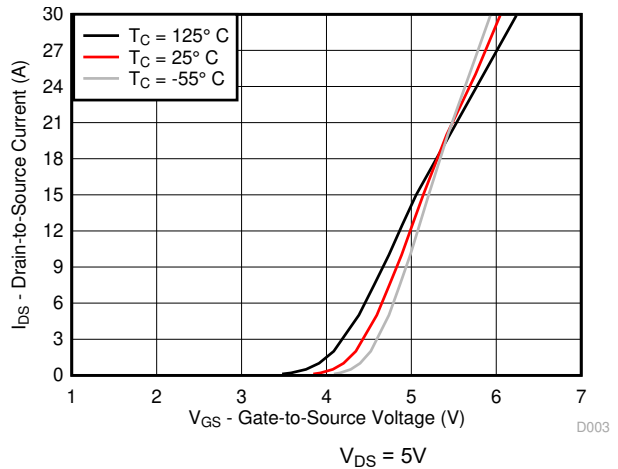


Figure 3-3. Transfer Characteristics

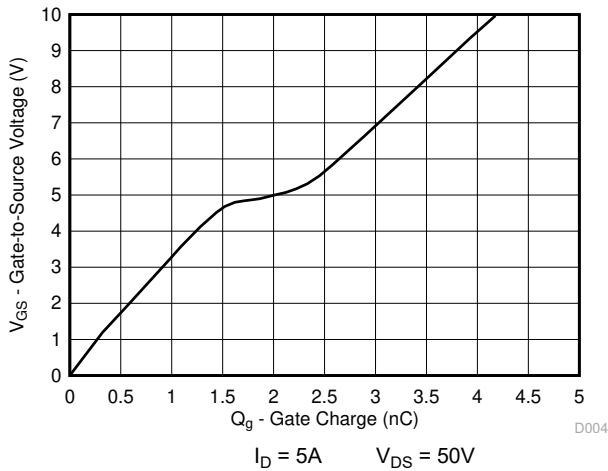


Figure 3-4. Gate Charge

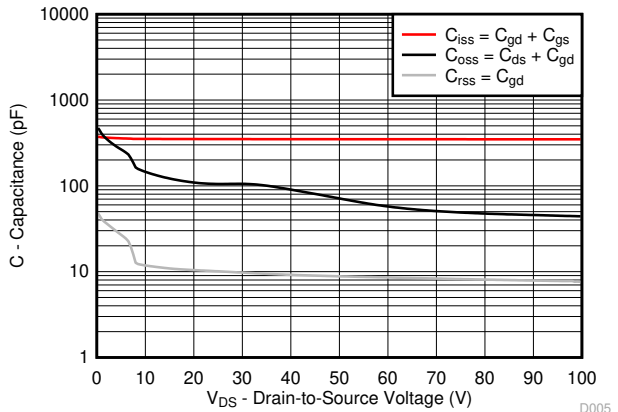


Figure 3-5. Capacitance

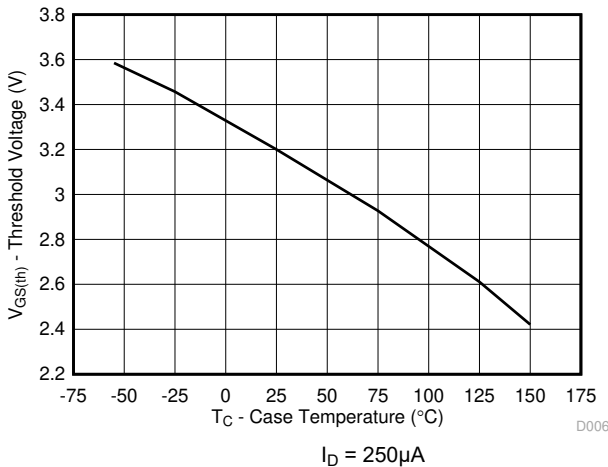


Figure 3-6. Threshold Voltage vs Temperature

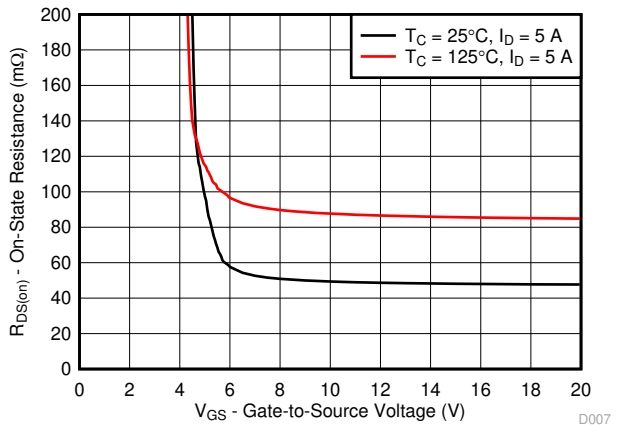


Figure 3-7. On-State Resistance vs Gate-to-Source Voltage

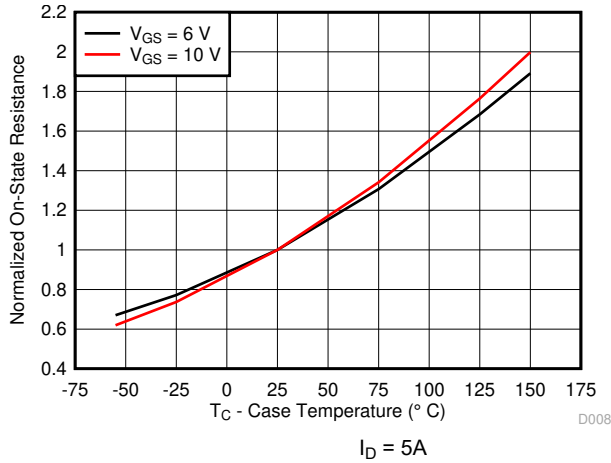


Figure 3-8. Normalized On-State Resistance vs Temperature

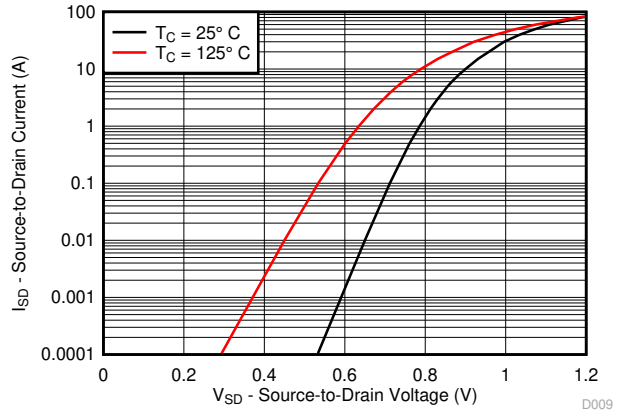


Figure 3-9. Typical Diode Forward Voltage

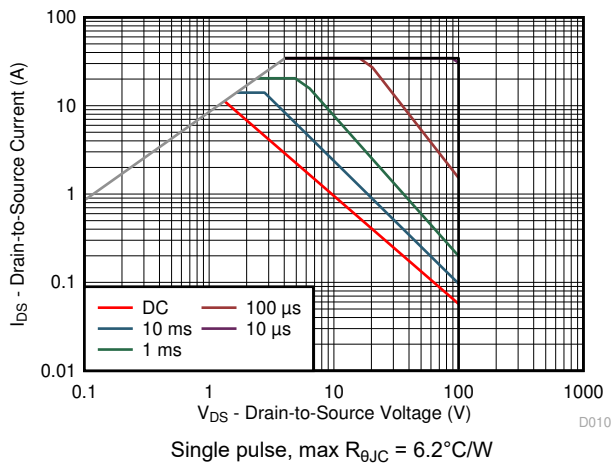


Figure 3-10. Maximum Safe Operating Area

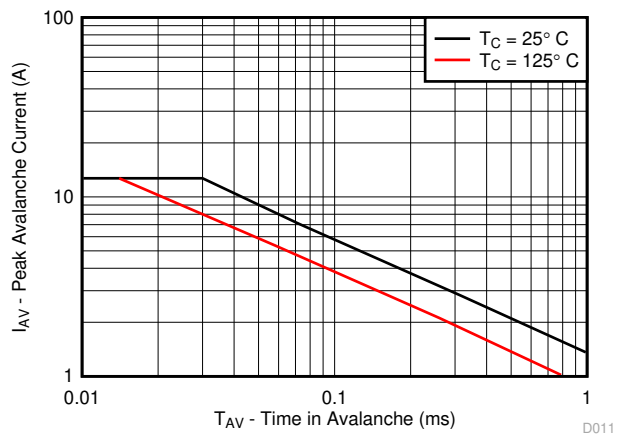


Figure 3-11. Single Pulse Unclamped Inductive Switching

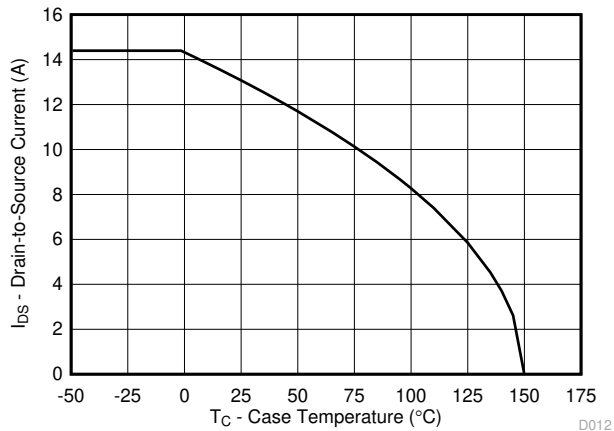


Figure 3-12. Maximum Drain Current vs Temperature

4 Device and Documentation Support

4.1 Third-Party Products Disclaimer

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4.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

4.3 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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4.4 Trademarks

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4.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

4.6 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

5 Revision History

Changes from Revision A (January 2017) to Revision B (March 2024) Page

- Updated the numbering format for tables, figures, and cross-references throughout the document..... 1

Changes from Revision * (July 2016) to Revision A (January 2017) Page

- Changed test voltage V_{DS} from 100V : to 50V in [Figure 3-2](#) curve..... 1
- Changed test voltage V_{DS} from 100V : to 50V in [Figure 3-4](#) 4

6 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | Eco Plan (2) | Lead finish/ Ball material (6) | MSL Peak Temp (3) | Op Temp (°C) | Device Marking (4/5) | Samples |
|------------------|---------------|--------------|-----------------|------|-------------|-----------------|--------------------------------------|----------------------|--------------|-------------------------|---------|
| CSD19538Q2 | ACTIVE | WSON | DQK | 6 | 3000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -55 to 150 | 1958 | Samples |
| CSD19538Q2R | ACTIVE | WSON | DQK | 6 | 10000 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -55 to 150 | 1958 | Samples |
| CSD19538Q2T | ACTIVE | WSON | DQK | 6 | 250 | RoHS & Green | NIPDAU | Level-1-260C-UNLIM | -55 to 150 | 1958 | Samples |

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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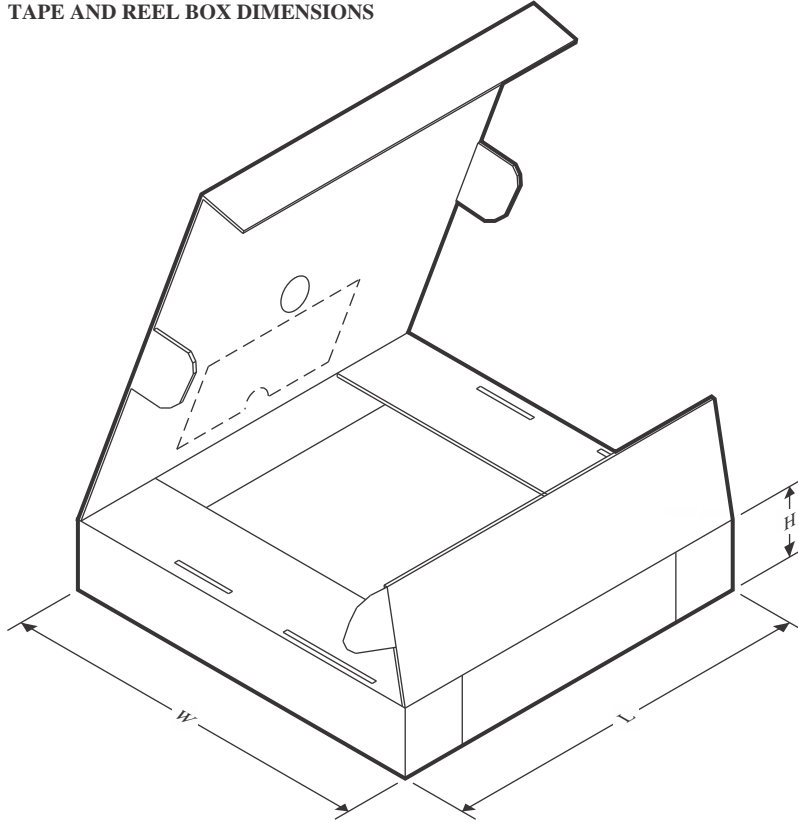
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|-------------|--------------|-----------------|------|------|--------------------|--------------------|---------|---------|---------|---------|--------|---------------|
| CSD19538Q2 | WSON | DQK | 6 | 3000 | 180.0 | 9.5 | 2.3 | 2.3 | 1.0 | 4.0 | 8.0 | Q1 |
| CSD19538Q2T | WSON | DQK | 6 | 250 | 180.0 | 9.5 | 2.3 | 2.3 | 1.0 | 4.0 | 8.0 | Q1 |

TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
|-------------|--------------|-----------------|------|------|-------------|------------|-------------|
| CSD19538Q2 | WSON | DQK | 6 | 3000 | 189.0 | 185.0 | 36.0 |
| CSD19538Q2T | WSON | DQK | 6 | 250 | 189.0 | 185.0 | 36.0 |

GENERIC PACKAGE VIEW

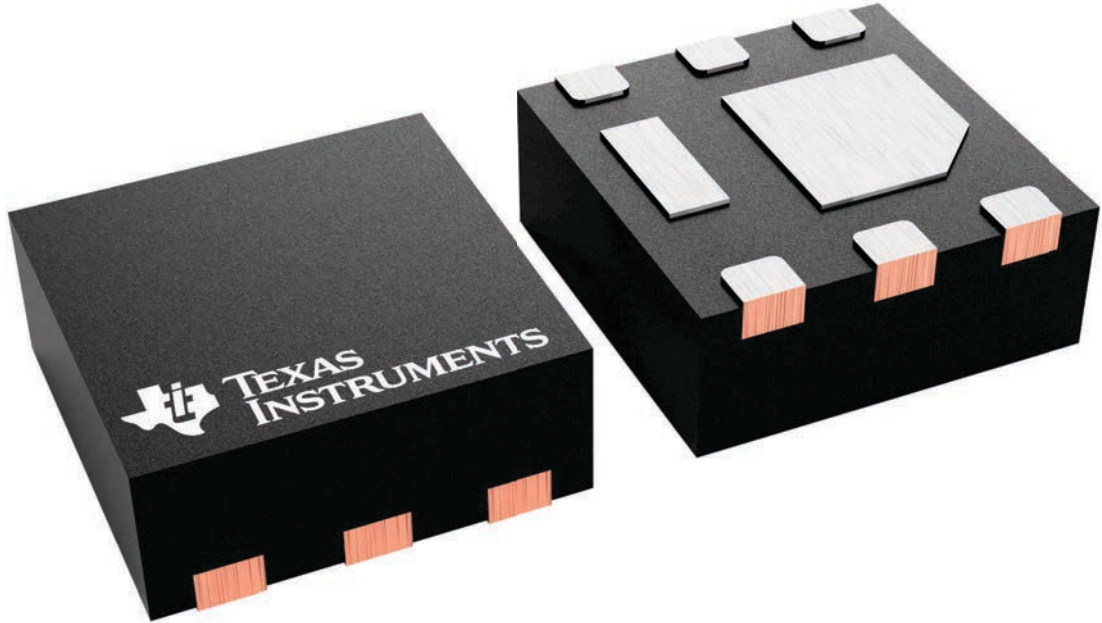
DQK 6

WSON - 0.8 mm max height

2 x 2, 0.65 mm pitch

PLASTIC SMALL OUTLINE - NO LEAD

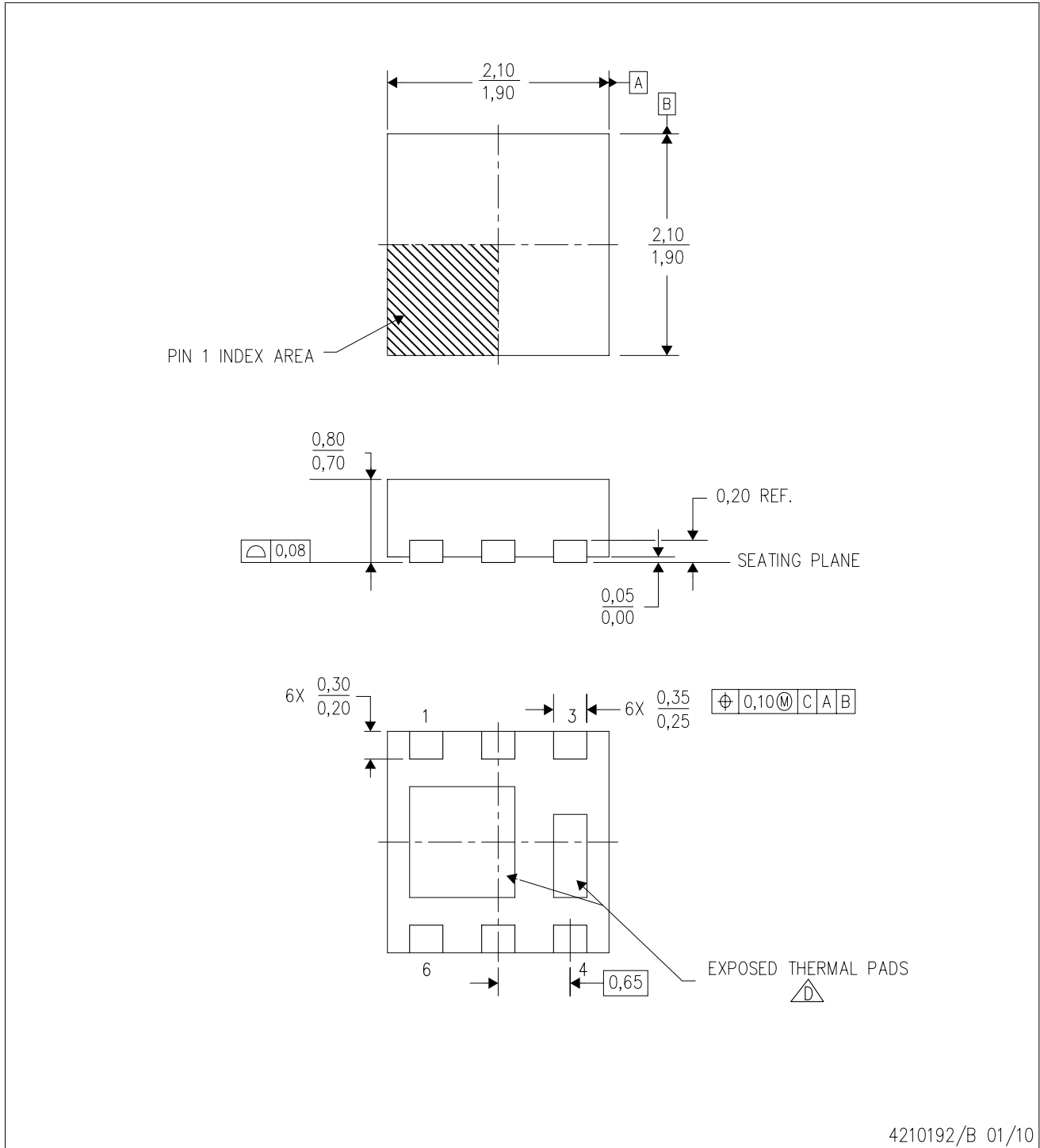
This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.




4229807/A

DQK (S-PWSON-N6)

PLASTIC SMALL OUTLINE NO-LEAD



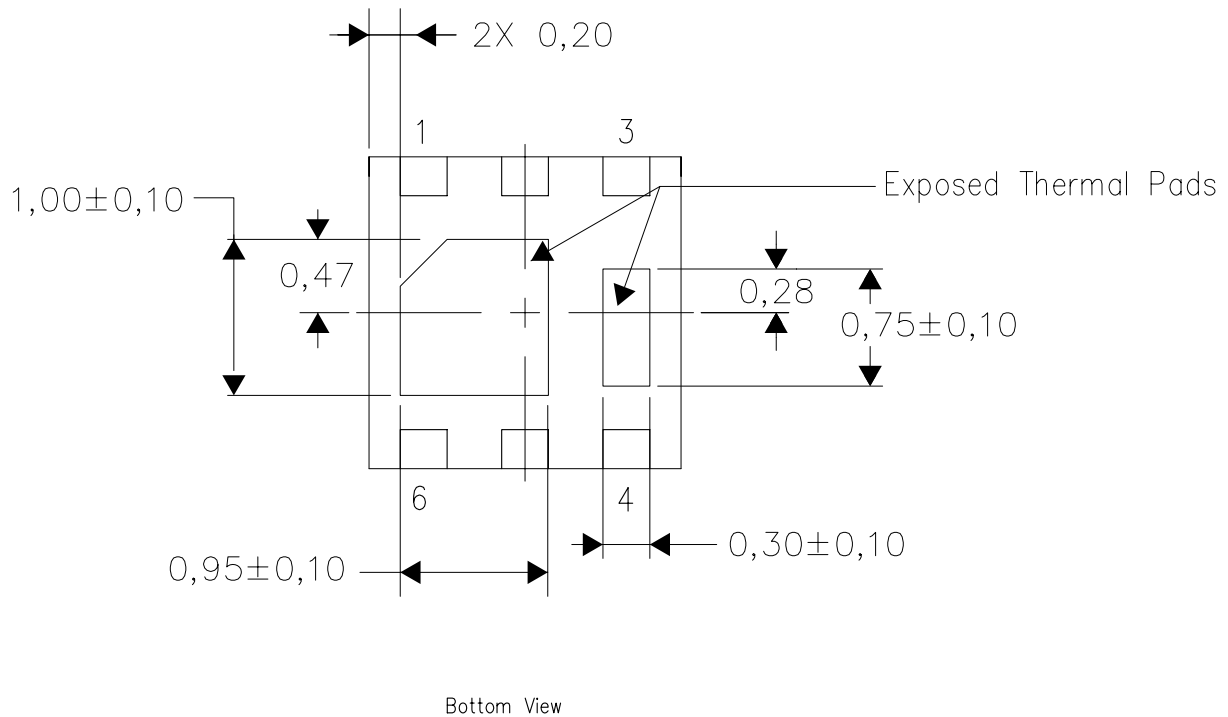
- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. Small Outline No-Lead (SON) package configuration.
 -  D. The package thermal pads must be soldered to the board for thermal and mechanical performance.

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No-Lead Logic Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

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